

## Sheet 1 of 1

	<u> </u>								
FORM PTO-1449				ATTY DOCKET NO.		SERIAL NO.			
INFORMATION DISCLOSURE STATEMENT			51473		10/661,051				
·				APPLICANT(S): Gallagher et al.					
				FILING DATE: 09/13/2003		ART UNIT: .1765			
	•	UNITED S	TATES PATENT	DOCUME	NTS				
EXAM. INITIAL		DOCUMENT NUMBER	DATE		NAME	CLASS	SUB CLASS	FIL. DATE IF APPR	
K-ic	AA	6,528,426	03/04/2003	C	Olsen et al.		-		
k-ic	AB	6,566,243	05/20/2003		Gaynor		_	1	
Kic	AC	6,589,865	07/08/2003	I	Dixit et al.	_	)	1	
		FORE	IGN PATENT DO	CUMENTS					
·		DOCUMENT NUMBER	DATE	C	COUNTRY	CLASS	SUB CLASS	TRAN YES/NO	
K-1C	ВА	354012500A	01/30/1979	Japan				Abstract	
,									
					·				
,									
	OTHER D	OCUMENTS (INCLUDIN	NG AUTHOR, TIT	LE, DATE, F	PERTINENT PA	GES, ETC	.)		
				-144	<del></del>				
				-					
							· · · · · · · · · · · · · · · · · · ·		
				-					
Examiner:	K - (	Alle		Date:	7-11-0	<u></u>			



## Sheet 1 of 1

FORM PTO-1449				ATTY DOCKET NO.		SERIAI	SERIAL NO.				
INFORMATION DISCLOSURE STATEMENT				51473		10/661,051					
IN ORMATION DISCESSIONE STATEMENT					APPLICANT(S): Gallagher et al.						
					LING DATE: 13/2003	ART UNIT: 1765					
		UNITED S	STATES PATENT	r DC	OCUMENTS						
EXAM. INITIAL		DOCUMENT NUMBER	DATE		NAME	CLASS	SUB CLASS	FIL. DATE IF APPR			
K-CL	AA	4,987,101	01/22/1991		Kaanta et al.		_				
	AB	5,103,288	04/07/1992		Sakamoto et al.		-				
	AC	5,266,126	11/30/1993		Deguchi		)				
	AD	5,324,683	06/28/1994		Fitch et al.	_	-				
	AE	5,461,003	10/24/1995		Havemann et al.	-					
	AF	5,668,398	09/16/1997		Havemann et al.	_	_				
·	AG	5,936,295	08/10/1999		Havemann et al.		_	<del></del>			
	AH	6,071,805	06/06/2000		Liu	_	-				
	AI	6,165,890	12/26/2000		Kohl et al.	_	_				
	AJ	6,261,942	07/17/2001		Zhou et al.	-	-				
	AK	6,316,347	11/13/2001		Chang et al.	-	_				
	AL	6,342,722	01/29/2002		Armacost et al.	_	_				
	AM	6,380,106	04/30/2002		Lim et al.		_				
Kec	AN	6,423,629	07/23/2002		Ahn et al.	_	-				
	OTHER I	OOCUMENTS (INCLUDI	NG AUTHOR, TIT	LE,	DATE, PERTINENT PA	GES, ETC	·.)				
K-11	BA	Kohl et al.; "Air-Gaps fo pp. 49-51 (1998).	or Electrical Interco	nne	ctions"; Electrochemical	and Solid S	Sate Letter	rs, 1 (1)			
						<del>-</del>					
				<del></del> ,		<del></del> -					
Examiner:	K.C.	Allen			Date: 7-1-	205					